

Pierre Godard

List of Publications by Year in descending order

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Version: 2024-02-01

26
papers

485
citations

933447

10
h-index

713466

21
g-index

27
all docs

27
docs citations

27
times ranked

521
citing authors

#	ARTICLE	IF	CITATIONS
1	In situ electrical and mechanical study of Indium Tin Oxide films deposited on polyimide substrate by Xe ion beam sputtering. <i>Thin Solid Films</i> , 2022, 741, 139035.	1.8	1
2	Strain ratio and thickness effects on plasticity and crack patterns of Nickel thin films. <i>Scripta Materialia</i> , 2022, 213, 114638.	5.2	4
3	X-ray ptychographic topography: A robust nondestructive tool for strain imaging. <i>Physical Review B</i> , 2021, 103, .	3.2	6
4	On the use of the scattering amplitude in coherent X-ray Bragg diffraction imaging. <i>Journal of Applied Crystallography</i> , 2021, 54, 797-802.	4.5	1
5	Strain ratio effects in mechanical properties of supported thin films. <i>Journal of Applied Physics</i> , 2020, 127, 105103.	2.5	6
6	90° ferroelectric domain switching effect on interfacial strain mediated magnetoelectric coupling. <i>Journal Physics D: Applied Physics</i> , 2020, 53, 145001.	2.8	3
7	Study of uniaxial deformation behavior of 50 nm-thick thin film of gold single crystal using in situ X-ray pole figure measurements. <i>Surface and Coatings Technology</i> , 2019, 377, 124878.	4.8	3
8	X-ray diffraction and stress relaxations to study thermal and stress-assisted annealings in nanocrystalline gold thin films. <i>Acta Materialia</i> , 2019, 173, 87-95.	7.9	4
9	In situ x-ray diffraction analysis of 2D crack patterning in thin films. <i>Acta Materialia</i> , 2019, 165, 177-182.	7.9	21
10	Visualization of Crystallographic Defects in InSb Micropillars by Ptychographic Topography. <i>Microscopy and Microanalysis</i> , 2018, 24, 18-21.	0.4	7
11	Plastic Deformation of InSb Micro-Pillars: A Comparative Study Between Spatially Resolved Laue and Monochromatic X-Ray Micro-Diffraction Maps. , 2018, , .		0
12	Relaxation mechanisms in a gold thin film on a compliant substrate as revealed by X-ray diffraction. <i>Applied Physics Letters</i> , 2017, 110, .	3.3	10
13	Continuous cyclic deformations of a Ni/W film studied by synchrotron X-ray diffraction. <i>Surface and Coatings Technology</i> , 2017, 332, 351-357.	4.8	5
14	Revealing crystalline domains in a mollusc shell single-crystalline prism. <i>Nature Materials</i> , 2017, 16, 946-952.	27.5	39
15	Nano-structuration effect on the mechanical behavior of gold thin films studied by 2D synchrotron x-ray diffraction. <i>Surface and Coatings Technology</i> , 2016, 308, 418-423.	4.8	2
16	Nondestructive three-dimensional imaging of crystal strain and rotations in an extended bonded semiconductor heterostructure. <i>Physical Review B</i> , 2015, 92, .	3.2	20
17	Strain in a silicon-on-insulator nanostructure revealed by 3D x-ray Bragg ptychography. <i>Scientific Reports</i> , 2015, 5, 9827.	3.3	52
18	Evidence of a Biological Control over Origin, Growth and End of the Calcite Prisms in the Shells of <i>Pinctada margaritifera</i> (Pelecypod, Pterioidea). <i>Minerals (Basel, Switzerland)</i> , 2014, 4, 815-834.	2.0	21

#	ARTICLE	IF	CITATIONS
19	X-ray lensless microscopy from undersampled diffraction intensities. Physical Review B, 2013, 88, .	3.2	32
20	Noise models for low counting rate coherent diffraction imaging. Optics Express, 2012, 20, 25914.	3.4	89
21	Imaging of highly inhomogeneous strain field in nanocrystals using x-ray Bragg ptychography: A numerical study. Physical Review B, 2011, 84, .	3.2	16
22	Three-dimensional high-resolution quantitative microscopy of extended crystals. Nature Communications, 2011, 2, 568.	12.8	142
23	Finite element modelling of induced gratings in nonlinear optics. , 2011, , .		0
24	Modelling of Induced Gratings in Nonlinear Optics. , 2010, , .		0
25	Scattering by a two-dimensional doped photonic crystal presenting an optical Kerr effect. COMPEL - the International Journal for Computation and Mathematics in Electrical and Electronic Engineering, 2009, 28, 656-667.	0.9	1
26	Time-Resolved X-Ray Stress Analysis in Multilayered Thin Films during Continuous Loading: Use of 2D Remote Detection. Advanced Materials Research, 0, 996, 878-883.	0.3	0